

Search Notes**Application/Control No.**

10/827,231

Examiner

Chuck Mah

Applicant(s)/Patent under Reexamination

HSIEH, JASON

Art Unit

3677

SEARCHED

Class	Subclass	Date	Examiner
16	337-341		
	303		
	330		
403	146		
	150		
	153-156		
361	680-683		
248	919-923		
		7/23/5	exp

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner